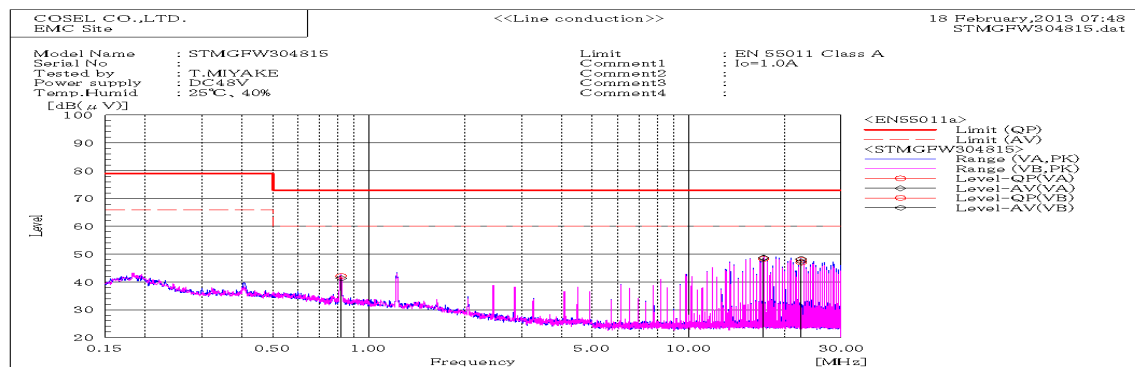
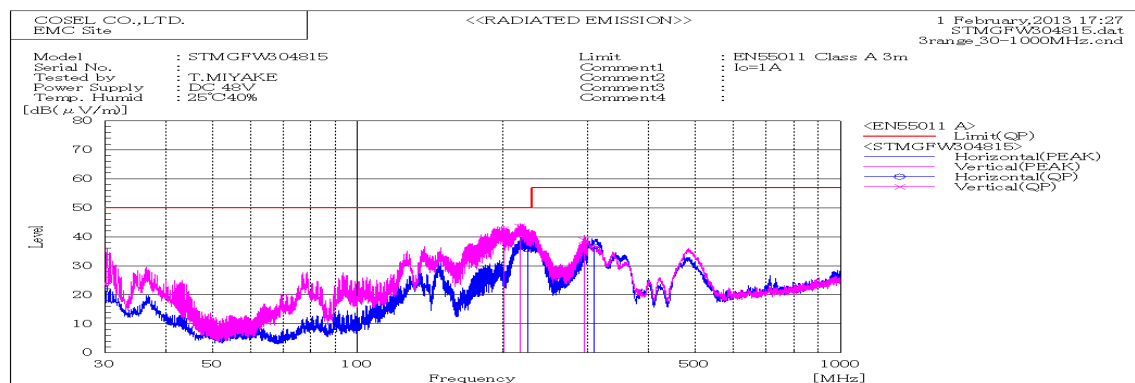


DATA SHEET		Date	18-Feb-13
Model	STMGFW304815	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



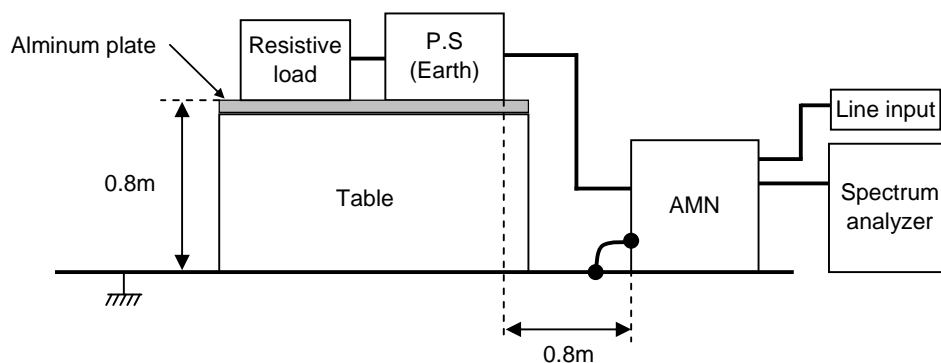
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.81924		VA	22	21.2	20.1	42.1	41.3	73	60	30.9	18.7	Pass	
17.1718		VB	27.2	27.6	21.1	48.3	48.7	73	60	24.7	11.3	Pass	
17.17235		VA	27.1	27.3	21.2	48.3	48.5	73	60	24.7	11.5	Pass	
22.48485		VB	25.9	26.2	21.1	47	47.3	73	60	26	12.7	Pass	
22.4848		VA	26.8	27.1	21.1	47.9	48.2	73	60	25.1	11.8	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
200.563	V	Stable	58.3		-15.8	42.5		50	7.5	Pass	105	318	
216.957	V	Stable	58.9		-15.4	43.5		50	6.5	Pass	101	317	
224.687	H	Stable	56.1		-20.3	35.8		50	14.2	Pass	121	272	
294.758	V	Stable	54.4		-15.6	38.8		57	18.2	Pass	105	167	
308.239	H	Stable	54		-17.3	36.7		57	20.3	Pass	103	260	

DATA SHEET		Date	18-Feb-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

## 1. Line conduction



## 2. Radiated emission

